

ON Semiconductor®

# FDS8884

# N-Channel PowerTrench® MOSFET

**30V**, **8.5A**, **23m** $\Omega$ 

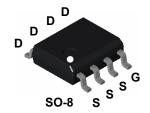
# **General Descriptions**

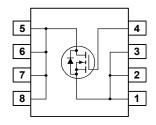
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $r_{\text{DS}(\text{on})}$  and fast switching speed.



#### **Features**

- Max  $r_{DS(on)} = 23m\Omega$  at  $V_{GS} = 10V$ ,  $I_D = 8.5A$
- Max  $r_{DS(on)} = 30m\Omega$  at  $V_{GS} = 4.5V$ ,  $I_D = 7.5A$
- Low gate charge
- 100% R<sub>G</sub> Tested
- RoHS Compliant





# **MOSFET Maximum Ratings** $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain to Source Voltage	30	V
$V_{GS}$	Gate to Source Voltage	±20	V
	Drain Current Continuous (Note 1a)	8.5	Α
ID	Pulsed	40	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	32	mJ
В	Power dissipation	2.5	W
$P_{D}$	Derate above 25°C	20	mW/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to 150	°C

### **Thermal Characteristics**

$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Case	(Note 1)	25	°C/W

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8884	FDS8884	SO-8	330mm	12mm	2500 units

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units		
Off Characteristics								
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V		
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to $25^{\circ}\text{C}$		23		mV/°C		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24V$ $V_{GS} = 0V$ $T_{J} = 125^{\circ}C$			1 250	μА		
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20V			±100	nA		

### On Characteristics (Note 3)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	1.7	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C		-4.9		mV/°C
	Drain to Source On Resistance	$V_{GS} = 10V, I_D = 8.5A,$		19	23	
rnac		$V_{GS} = 4.5V$ , $I_{D} = 7.5A$ ,		23	30	mΩ
r <sub>DS(on)</sub>	Brain to Gource Off Hesistance	$V_{GS} = 10V, I_D = 8.5A,$ $T_J = 125^{\circ}C$		26	32	1115.2

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	\/_	475	635	рF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1MHz	100	135	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	11 = 11VII 12	65	100	pF
$R_{G}$	Gate Resistance	f = 1MHz	0.9	1.6	Ω

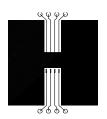
### **Switching Characteristics (Note 3)**

t <sub>d(on)</sub>	Turn-On Delay Time		5	10	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 15V, I_{D} = 8.5A$ $V_{GS} = 10V, R_{GS} = 33\Omega$	9	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10V, H <sub>GS</sub> = 3322	42	68	ns
t <sub>f</sub>	Fall Time		21	34	ns
Qg	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 10V$ $I_{D} = 8.5A$	9.2	13	nC
$Q_g$	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 5V$	5.0	7	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 8.5A	1.5		nC
Q <sub>gd</sub>	Gate to Drain Charge		2.0		nC

### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Voltage	$I_{SD} = 8.5A$	0.9	1.25	V
		I <sub>SD</sub> = 2.1A	0.8	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 8.5A$ , di/dt = 100A/ $\mu$ s		33	ns
Q <sub>rr</sub>	Reverse Recovery Charge			20	nC

<sup>1:</sup> R<sub>B,IA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>B,C</sub> is guaranteed by design while R<sub>B,CA</sub> is determined by the user's board design.



a) 50°C/W when mounted on a 1 in2 pad of 2 oz copper



b) 105°C/W when mounted on a .04 in<sup>2</sup> pad of 2 oz copper



c) 125°C/W when mounted on a minimun pad

Scale 1: 1 on letter size paper

<sup>2:</sup> Starting  $T_J$  = 25°C, L = 1mH, I<sub>AS</sub> = 8A, V<sub>DD</sub> = 27V, V<sub>GS</sub> = 10V. 3: Pulse Test:Pulse Width <300 $\mu$ S, Duty Cycle <2%.



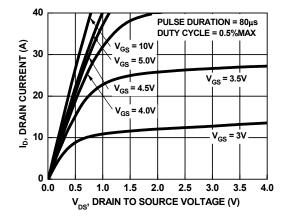


Figure 1. On Region Characteristics

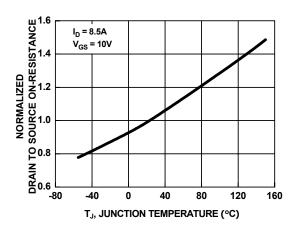


Figure 3. Normalized On Resistance vs Junction Temperature

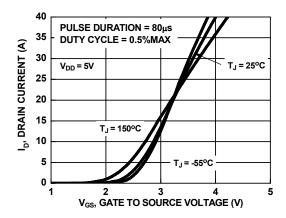


Figure 5. Transfer Characteristics

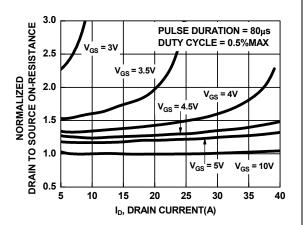


Figure 2. Normalized On-Resistance vs Drain current and Gate Voltage

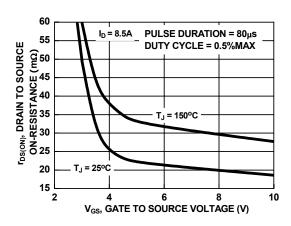


Figure 4. On-Resistance vs Gate to Source Voltage

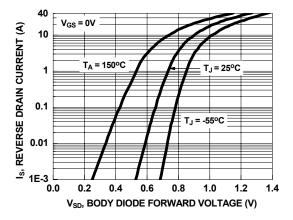


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



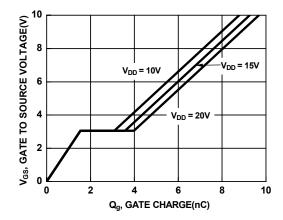


Figure 7. Gate Charge Characteristics

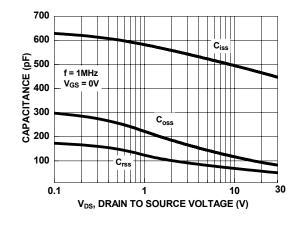


Figure 8. Capacitance vs Drain to Source Voltage

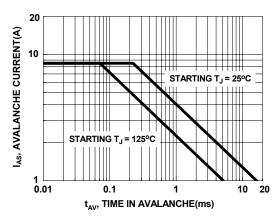


Figure 9. Unclamped Inductive Switching Capability

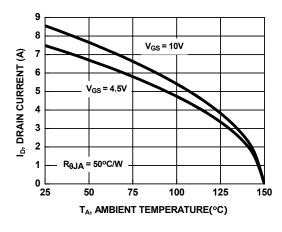


Figure 10. Maximum Continuous Drain Current vs
Ambient Temperature

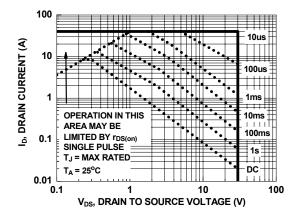


Figure 11. Forward Bias Safe Operating Area

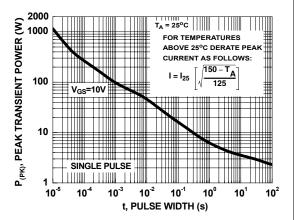
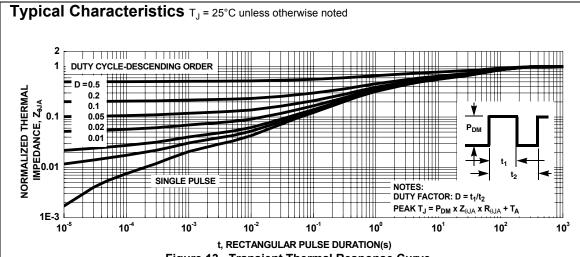


Figure 12. Single Pulse Maximum Power Dissipation



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